Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/615,404	ONOE ET AL.	
Examiner	Art Unit	
TAN X. DINH	2627	

SEARCHED						
Class	Subclass	Date	Examiner			

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	-			
Interference Search History Printout		8/22/2006	T.D	

SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
EAST (see search history printout)	8/22/2006	T.D